

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/647,666	MEIER ET AL.	
Examiner	Art Unit	
Leslie J. Evanisko	2854	

	SEARCHED	
Class	Subclass	Date Examiner
searcl	updated	3/29/2006 LJE
400	32 36 207	
	208.1 209	
	237 240.3	
	240.4 691	
	692 693	
	693.1	
	120.01	
	120.02	
	120.03	
	120.04	
l	120.16	
400	120.17	3/29/2006 LJE
347	172 176 177	3/29/2006 LJE

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
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347	178 214	3/29/2006	LJE
			

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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